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APPLICATION NO.	FILING DATE	FIRST NAMED INVENTOR	ATTORNEY DOCKET NO.	CONFIRMATION NO.
10/780,140	02/17/2004	William E. Dougherty JR.	YOR920030437US1 (8728-653)	9678
46069 7590 11/20/2007 F. CHAU & ASSOCIATES, LLC 130 WOODBURY ROAD WOODBURY, NY 11797			EXAMINER DINH, PAUL	
			ART UNIT 2825	PAPER NUMBER
			MAIL DATE 11/20/2007	DELIVERY MODE PAPER

Please find below and/or attached an Office communication concerning this application or proceeding.

The time period for reply, if any, is set in the attached communication.

Office Action Summary

Application No.

10/780,140

Applicant(s)

DOUGHERTY ET AL.

Examiner

Paul Dinh

Art Unit

2825

-- The MAILING DATE of this communication appears on the cover sheet with the correspondence address --

Period for Reply

A SHORTENED STATUTORY PERIOD FOR REPLY IS SET TO EXPIRE 3 MONTH(S) OR THIRTY (30) DAYS, WHICHEVER IS LONGER, FROM THE MAILING DATE OF THIS COMMUNICATION.

- Extensions of time may be available under the provisions of 37 CFR 1.136(a). In no event, however, may a reply be timely filed after SIX (6) MONTHS from the mailing date of this communication.
- If NO period for reply is specified above, the maximum statutory period will apply and will expire SIX (6) MONTHS from the mailing date of this communication.
- Failure to reply within the set or extended period for reply will, by statute, cause the application to become ABANDONED (35 U.S.C. § 133). Any reply received by the Office later than three months after the mailing date of this communication, even if timely filed, may reduce any earned patent term adjustment. See 37 CFR 1.704(b).

Status

- 1) ☒ Responsive to communication(s) filed on 05 November 2007.
- 2a) ☒ This action is **FINAL**. 2b) ☐ This action is non-final.
- 3) ☐ Since this application is in condition for allowance except for formal matters, prosecution as to the merits is closed in accordance with the practice under *Ex parte Quayle*, 1935 C.D. 11, 453 O.G. 213.

Disposition of Claims

- 4) ☒ Claim(s) 1-20 is/are pending in the application.
- 4a) Of the above claim(s) _____ is/are withdrawn from consideration.
- 5) ☐ Claim(s) _____ is/are allowed.
- 6) ☒ Claim(s) 1-20 is/are rejected.
- 7) ☐ Claim(s) _____ is/are objected to.
- 8) ☐ Claim(s) _____ are subject to restriction and/or election requirement.

Application Papers

- 9) ☐ The specification is objected to by the Examiner.
- 10) ☐ The drawing(s) filed on _____ is/are: a) ☐ accepted or b) ☐ objected to by the Examiner.
Applicant may not request that any objection to the drawing(s) be held in abeyance. See 37 CFR 1.85(a).
Replacement drawing sheet(s) including the correction is required if the drawing(s) is objected to. See 37 CFR 1.121(d).
- 11) ☐ The oath or declaration is objected to by the Examiner. Note the attached Office Action or form PTO-152.

Priority under 35 U.S.C. § 119

- 12) ☐ Acknowledgment is made of a claim for foreign priority under 35 U.S.C. § 119(a)-(d) or (f).
- a) ☐ All b) ☐ Some * c) ☐ None of:
- ☐ Certified copies of the priority documents have been received.
 - ☐ Certified copies of the priority documents have been received in Application No. _____.
 - ☐ Copies of the certified copies of the priority documents have been received in this National Stage application from the International Bureau (PCT Rule 17.2(a)).
- * See the attached detailed Office action for a list of the certified copies not received.

Attachment(s)

- ☐ Notice of References Cited (PTO-892)
- ☐ Notice of Draftsperson's Patent Drawing Review (PTO-948)
- ☐ Information Disclosure Statement(s) (PTO/SB/08)
Paper No(s)/Mail Date _____
- ☐ Interview Summary (PTO-413)
Paper No(s)/Mail Date. _____
- ☐ Notice of Informal Patent Application
- ☐ Other: _____

DETAILED ACTION

This **FINAL** office action is a response to the remarks filed on 11/5/07.

The remarks are not persuasive; therefor, the rejections based on Weaver and McElvain are maintained.

Claims 1-20 are pending.

Claim Rejections - 35 USC § 102

The following is a quotation of the appropriate paragraphs of 35 U.S.C. 102 that form

The basis for the rejections under this section made in this Office action:

A person shall be entitled to a patent unless –

(e) The invention was described in (1) an application for patent, published under section 122(b), by another filed in the United States before the invention by the applicant for patent or (2) a patent granted on an application for patent by another filed in the United States before the invention by the applicant for patent, except that an international application filed under the treaty defined in section 351(a) shall have the effects for purposes of this subsection of an application filed in the United States only if the international application designated the United States and was published under Article 21(2) of such treaty in the English language.

1. Claim 1 and similarly recited claims 13 and 14 are rejected under 35 U.S.C. 102(e) as being anticipated by the prior art of record Weaver (US pub. 2004/0230933)

Receiving a RTL textual description of a circuit design model as input to a logical synthesis stage (*par 0015 (design synthesis reads RTL code and synthesizes the code)*);
and

Performing logical synthesis using the RTL textual description (*par 0015 (design synthesis reads RTL code and synthesizes the code)*), the logical synthesis being performed before assigning physical locations to the circuits (*see the figure (only one figure), the design (logical) synthesis 2 being performed before assigning physical locations (Placement block 6)*), wherein performing logical synthesis comprises:

Generating a logic network from the RTL textual description of the circuit design model (*the figure show a logic/digital network/circuit generated from the above mentioned RTL*); determining a structural metric through an analysis of the logic network, **wherein the structural metric is a measure of wiring congestion (block 8)** of the circuit design model; and

Using the structural metric during the logical synthesis to predict wiring congestion of the circuit design model to optimize the circuit design model

(See the loop/iteration in the figure, during the design (logical) synthesis 2 iteration, the structural metric is a measure of wiring congestion (block 8) predicts/estimates/determines/detects/considers wiring congestion of the circuit design model to optimize the circuit design model)

2. Claims 1-20 are rejected under 35 U.S.C. 102(e) as being anticipated by the prior art of record McElvain (US pub 2006/0095872)

(Claim 1 and similarly recited claims 13 and 14)

Receiving a RTL textual description of a circuit design model as input to a logical synthesis stage (*par 01123: RTL description which can then be further processed in a logic synthesis process*); and

Performing logical synthesis (fig 22) using the RTL textual description (*par 01123: RTL description which can then be further processed in a logic synthesis process*), the logical synthesis being performed before assigning physical locations to the circuits (*fig 22, the logical synthesis 1001 being performed before assigning physical locations (1003)*), wherein performing logical synthesis comprises:

Generating a logic network from the RTL textual description of the circuit design model (*par 0123: RTL description which can then be further processed in a logic synthesis process 1001. Logic Synthesis operation 1001 performs logic synthesis to create a logic element network*);

Determining a structural metric through an analysis of the logic network, **wherein the structural metric is a measure of wiring congestion** (*see wherein the structural metric is a measure of wiring congestion in fig 23, 35*) of the circuit design model; and

Using the structural metric during the logical synthesis (fig 22) to predict wiring congestion of the circuit design model to optimize the circuit design model

(Par 0123: Some (or all) of operations 1001-1005 may be **repeated in iterations** to satisfy the design requirement and to optimize the design. Thus, In a similar manner to above-mentioned Weaver, it is the iterations of operations 1001-1005 in fig 22 that makes the wiring congestion prediction/consideration/analysis/detection/**estimation possible during logical synthesis simply due to the loop/iteration**. This is exactly shown in fig 2 of the instant application, the prediction/consideration/analysis/detection/estimation of wiring congestion (120) during logical synthesis made possible due to the loop/iteration. In fact, the prediction/consideration/analysis/detection/estimation of wiring congestion **(120) performed after both physical layout and the synthesis;** then wiring congestion prediction **during logic synthesis** is simply a matter of looping/iteration as taught by McElvain in par 0123 Some (or all) of operations 1001-1005 may be **repeated in iterations** to satisfy the design requirement and to optimize the design)

(Claim 2) wherein using the structural metric to optimize circuit design model comprises adding, deleting or substituting one or more circuits using a combination of Boolean, algebraic and electrical optimizations (fig 22, 26, 35, 43-44).

(Claims 3, 15) wherein the structural metric includes a measure of routing congestion of the circuit design model after placement and routing design (fig 23, 35, par 0111, 0126), the routing congestion being measured by an average and a peak number of wires crossing any bisection of the placed and routed circuit design model (i.e., fig 15, 37-41, par 0109, 0111, 0126)

(Claims 4-5) wherein using the structural metric to optimize the circuit design model comprises using the structural metric: during a technology independent synthesis stage of the logic synthesis stage (fig 22, 35); during the technology mapping stage of the logic synthesis (fig 22, 35).

(Claim 6) wherein using the structural metric during the logic synthesis stage to optimize the circuit design comprises using the structural metric during a buffering stage of the logic synthesis stage (fig 26, par 0011, 0122)

(Claims 7-9, 16-18) further comprising incrementally updating the structural metric when logic changes are made to the circuit design model comprises: performing recomputation on circuits involved in an optimization and circuits affected by the optimization to provide a structural metric cost (fig 22, 43-44); maintaining information regarding circuits affected by an optimization, which are computed when recomputation of the structural metric is necessary (fig 22, 43-44).

(Claims 10, 19) wherein creating the structural metric comprises **any one of** a distance metric, a sum-of-all-pairs-min-cut ("SAPMC"), expansion metric (any one of fig 26, 28-29)

(Claims 11, 20) wherein determining a structural metric comprises: generating **one or more** possible optimizations (this invention about generating one or more possible optimizations i.e., cost, components, power, area, delay, reduction/minimizing manual work, cut, net, congestion, hardware, distance, wire lengths, etc.); incrementally updating the structural metric when the optimizations are made to the circuit design to evaluate the cost of applying each of the **one or more** possible optimizations to the circuit design necessary (fig 22, 43-44), the structural metric comprising **any one of** a distance metric, a sum-of-all-pairs-min-cut ("SAPMC"), and an expansion metric (any one of fig 26, 28-29); evaluating a structural metric cost of each of the **one or more** possible optimizations as given by the structural metric (fig 22, 43-44); selecting an optimization from the *one or more* possible optimizations with the lowest structural metric cost (par 0013, 0104); and applying the optimization to the circuit (fig 22, 43-44)

(Claim 12) wherein generating the **one or more** possible optimizations comprises: generating a structure-driven kernel factoring; generating a structure-driven decomposition; generating a structure-driven tech mapping; and generating a structure-aware buffering (i.e., fig 26, par 0005, 0123).

Response to Applicant Remarks

Turning first to Weaver, the Applicant states that:

Weaver does not disclose or suggest the limitation of "*determining a structural metric through an analysis of the logic network, wherein the structural metric is a*

measure of wiring congestion of the circuit design model", as essentially recited in claims 1, 13, and 14; and

Congestion is considered after placement of the cells. However, the claim step of determining a structural metric, (*wherein the structural metric is a measure of wiring congestion*) is performed during logical synthesis, which is before placement. As discussed above, claims 1, 13, and 14.

Examiner Response:

Weaver does disclose or suggest the limitation of "determining a structural metric through an analysis of the logic network, wherein the structural metric is a measure of wiring congestion (block 8) of the circuit design model"; Logic/digital network/circuit is shown in the figure; and

Determining a structural metric, (*wherein the structural metric is a measure of wiring congestion (block 8)*) is performed during logical synthesis, which is before placement.

(See the loop/iteration in the figure, during the design (logical) synthesis 2 iteration in the loop feeding back to the synthesis which is before placement; the structural metric is a measure of wiring congestion (block 8) predicts/estimates/determines/detects/considers wiring congestion of the circuit design model to optimize the circuit design model)

Note:

- a. above interpretation and the Weaver proof and evidence disclose exactly what is claimed; and
- b. In figure 2 of the instant Application, note the wiring congestion prediction (120) also performed after the Physical synthesis, what makes during synthesis and before physical happen as claimed is simply due to the loop/iteration feeding back to the synthesis; this is exactly taught by Weaver in the figure, i.e., wiring congestion prediction (8) performed during synthesis (2) and before physical/placement (6) is simply due to the loop/iteration feeding back to the synthesis

Turning second to McElvain, the Applicant states that:

- a. McElvain does not disclose or suggest the limitation of "*generating a logic network from the RTL textual description of the circuit design model and determining a structural metric through an analysis of the logic network, wherein the*

structural metric is a measure of wiring congestion of the circuit design model", as essentially recited in claims 1, 13, and 14; and

b. McElvain does not consider congestion until after logic synthesis and fig 22 shows that optimization 1005 take places after logic synthesis 1001 and the claimed determining of the structural metric (wherein the structural metric is a measure of wiring congestion) is performed during logic synthesis. McElvain also performs its optimization 1005 after placement of the circuits, which is different from the amended claims, which recite the determining of the structural metric being performed before placement of the circuits. While element 1450 of figure 35 shows production of a congestion estimate, as written in element 1450, the estimation is performed after the placement of the circuits, which is different from the amended claims.

Examiner Response:

Regarding (a): McElvain does disclose or suggest the limitation of "*generating a logic network from the RTL textual description of the circuit design model (par 0123: RTL description which can then be further processed in a logic synthesis process 1001. Logic Synthesis operation 1001 performs logic synthesis to create a logic element network) and determining a structural metric through an analysis of the logic network, wherein the structural metric is a measure of wiring congestion of the circuit design model (see wherein the structural metric is a measure of wiring congestion in fig 23, 35)*"

Regarding (b): McElvain does consider congestion during logic synthesis; i.e.

Par 0123: Some (or all) of operations 1001-1005 may be repeated in iterations to satisfy the design requirement and to optimize the design. Thus, In a similar manner to above-mentioned Weaver, it is the iterations of operations 1001-1005 in fig 22 that makes the wiring congestion prediction/consideration/analysis/detection/estimation possible during logical synthesis simply due to the loop/iteration simple due to the loop/iteration feeding back to the synthesis and (make it before placement). This is exactly shown in fig 2 of the instant application, the prediction/consideration/analysis/detection/estimation of wiring congestion (120) during logical synthesis made possible due to the loop/iteration feeding back to the synthesis. In fact, in the instant application, the prediction/consideration/analysis/detection/estimation of wiring congestion (120) performed after both physical layout and the synthesis; then wiring congestion prediction during logic synthesis is simply a matter of looping/iteration feeding back to the synthesis as taught by McElvain in par 0123 " Some (or all) of

operations 1001-1005 may be **repeated in iterations** to satisfy the design requirement and to optimize the design; thus not only reads on the **during logic synthesis issue** as claimed in claims 1, 13-14) but also satisfy/cover the Applicant disclosure

Regarding the argument that the estimation is performed after the placement of the circuits, which is different from the amended claims; the examiner points out that Par 0123 discloses: “**Some (or all) of operations 1001-1005 may be repeated in iterations to satisfy the design requirement and to optimize the design**”. Thus, In a similar manner to above-mentioned Weaver, it is the iterations of operations 1001-1005 in fig 22 that makes the prediction/consideration/analysis/detection/estimation of wiring congestion **possible during logical synthesis simply due to the loop/iteration feeding back to the synthesis that make the “during synthesis happens”**. This is exactly shown in fig 2 of the instant application, the prediction/consideration/analysis/detection/estimation of wiring congestion (120) **during logical synthesis** made possible due to the loop/iteration **feeding back to the synthesis that make the “during synthesis happens”**. In fact, the prediction/consideration/analysis/detection/estimation of wiring congestion (120) **performed after both physical layout and the synthesis**; then wiring congestion prediction **during logic synthesis** is simply a matter of looping/iteration **feeding back to the synthesis that make the “during synthesis happens”** as taught by McElvain in par 0123: Some (or all) of operations 1001-1005 may be **repeated in iterations** to satisfy the design requirement and to optimize the design;

Thus **not only reads on the during logic synthesis issue** as claimed in claims 1, 13-14) but also satisfy/cover the Applicant disclosure.

Correspondence Information

THIS ACTION IS MADE FINAL. Applicant is reminded of the extension of time policy as set forth in 37 CFR 1.136(a).

A shortened statutory period for reply to this final action is set to expire THREE MONTHS from the mailing date of this action. In the event a first reply is filed

within TWO MONTHS of the mailing date of this final action and the advisory action is not mailed until after the end of the THREE-MONTH shortened statutory period, then the shortened statutory period will expire on the date the advisory action is mailed, and any extension fee pursuant to 37 CFR 1.136(a) will be calculated from the mailing date of the advisory action. In no event, however, will the statutory period for reply expire later than SIX MONTHS from the date of this final action.

Any inquiry concerning this communication or earlier communications from the examiner should be directed to Paul Dinh whose telephone number is 571-272-1890. If attempts to reach the examiner by telephone are unsuccessful, the examiner's Supervisor, Jack Chiang can be reached on 571-272-7483. The fax number for the organization where this application or proceeding is assigned is 571-273-8300.

Information regarding the status of an application may be obtained from the Patent Application Information Retrieval (PAIR) system. Status information for published applications may be obtained from either Private PAIR or Public PAIR. Status information for unpublished applications is available through Private PAIR only. For more information about the PAIR system, see <http://pair-direct.uspto.gov>. Should you have questions on access to the Private PAIR system, contact the Electronic Business Center (EBC) at 866-217-9197 (toll-free). If you would like assistance from a USPTO Customer Service Representative or access to the automated information system, call 800-786-9199 (IN USA OR CANADA) or 571-272-1000.

Paul Dinh

Primary Examiner

A handwritten signature in black ink that reads "Paul Dinh". The signature is written in a cursive, flowing style with a long horizontal stroke at the end.